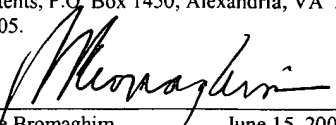


Certificate of Mailing Under 37 CFR 1.8

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Sue Bromaghin

June 15, 2005

**CUSTOMER NO. 36257**

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Anatoly FABRIKANT et al.  
Title: System for Scatterometric Measurements and Applications  
Application No.: 09/671,715 Filing Date: September 27, 2000  
Examiner: Zandra V. SMITH Group Art Unit: 2877  
Docket No.: TNCR.188US0 Conf. No.: 6087

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Alexandria, VA 22313-1450

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Sir:

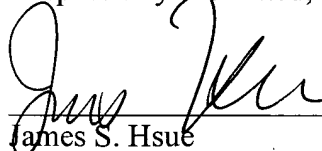
Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicant(s) call(s) the documents listed on the enclosed Form PTO-1449 to the Examiner's attention in this patent application.

- ☒ According to 37 C.F.R. 1.98(2)(ii), copies of the U.S. Patents and U.S. Published Patent Applications documents are not required and are therefore not enclosed. Copies of the listed foreign patent documents or Other Art are enclosed.

Citation of these documents shall not be construed as (1) an admission that the documents are prior art with respect to the invention or inventions claimed in this application, (2) a representation that a search has been made (other than as indicated by any cited document), or (3) an admission that the cited information is, or is considered to be, material to patentability as defined in § 1.56(b).

This information disclosure statement is submitted under 37 C.F.R. § 1.97(b) and consequently no fee should be required. The Commissioner is authorized, however, to charge any fee that may be required, or to credit any overpayment, against Deposit Account No. 502664. This form is being submitted in duplicate.

Respectfully submitted,



James S. Hsue  
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June 15, 2005  
Date

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U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.		
INFORMATION DISCLOSURE STATEMENT BY APPLICANT				TNCR.188US0 (formerly M-10699 US)		09/671,715		
				Applicant(s)		Conf. No.		
(Use several sheets if necessary)				Anatoly FABRIKANT et al.		6087		
(Form PTO-1449)				Filing Date		Art Group		
				September 27, 2000		2877		
<b>U.S. Patent Documents</b>								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
	A1	6,768,967 B2	07/27/2004	JOHNSON et al.	702	179		
	A2	6,097,488	08/01/2000	GREK et al.	356	364		
	A3	5,739,909	04/14/1998	BLAYO et al.	356	369		
	A4	5,751,427	05/12/1998	DE GROOT	356	358		
	A5	6,268,916 B1	07/31/2001	LEE et al.	356	364		
	A6	5,900,939	05/04/1999	ASPINES et al.	356	369		
	A7	5,978,074	11/02/1999	OPSAL et al.	356	72		
<b>U.S. Published Patent Application Documents</b>								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<b>Foreign Patent Documents</b>								
							Translation	
		Document	Date	Country	Class	Subclass	Yes	No
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>								
	D1	US Provisional Appln. No. 60/224,451, filed 08/10/2000, to STANKE et al., cited in USP 6,768,967, 28 pgs.						
	D2	LI, "Formulation and Comparison of Two Recursive Matrix Algorithms for Modeling Layered Diffraction Gratings", J. Opt. Soc. Am. A/Vol. 13, No. 5 / May 1996, pp. 1024-1035.						
	D3	International Search Report from corresponding PCT Appln. PCT/US01/30063, dated 12/21/01, 4 pages.						
	D4	Written Opinion from corresponding PCT Appln. PCT/US01/30063, dated 9/18/2002, 5 pages.						
	D5	International Preliminary Examination Report from corresponding PCT Appln. PCT/US01/30063, dated 1/16/2003, 6 pages.						
	D6	Patent Search conducted on August 1, 2000 (53 pages).						
Examiner			Date Considered					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

U.S. Department of Commerce, Patent and Trademark				Atty. Docket No.		Application No.		
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U.S. Published Patent Application Documents								
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate		
Foreign Patent Documents								
							Translation	
	Document	Date	Country	Class	Subclass	Yes	No	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)								
	D7	BLAYO et al., "Ultraviolet-Visible Ellipsometry for Process Control During the Etching of Submicrometer Features" J. Opt. Soc. Am. A., vol. 12, No. 3, Mar. 1995, pp. 591-599.						
	D8	SCHRAMM et al., "Algorithm Implementation and Techniques for Providing More Reliable Overlay Measurements and Better Tracking of the Shallow Trench Isolation (STI) Process", SPIE: Conference on Metrology, Inspection, and Process Control of Microlithography XIII., Mar. 1999, pp. 116-122.						
	D9	MOHARAM, "Coupled-Wave Analysis of Two-Dimensional Dielectric Gratings", SPIE: Vol. 883; Holographic Optics: Design and Applications (1988), pp. 8-11.						
	D10	International Application Pub. No. WO02/50501 A1, published with International Search Report on June 27, 2002.						
	D11	MOHARAM et al., "Formulation for Stable and Efficient Implementation of the Rigorous Coupled-Wave Analysis of Binary Gratings", J. Opt. Soc. Am. A./Vol. 12, No. 5, May 1995, pp. 1068-1076.						
Examiner			Date Considered					
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your communication to applicant.								

